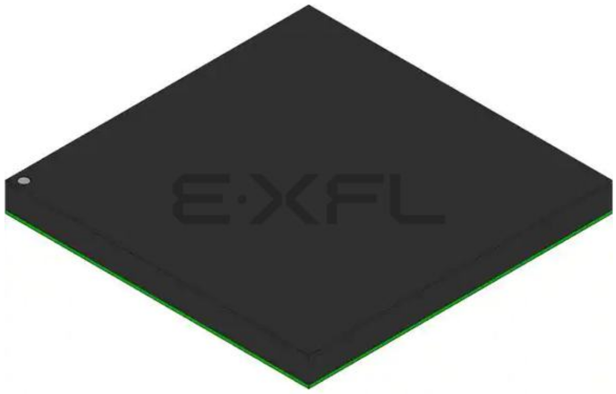
Altera - EP1SGX40DF1020I6N Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	624
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=ep1sgx40df1020i6n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

The logic array consists of LABs, with 10 logic elements (LEs) in each LAB. An LE is a small unit of logic providing efficient implementation of user logic functions. LABs are grouped into rows and columns across the device.

M512 RAM blocks are simple dual-port memory blocks with 512 bits plus parity (576 bits). These blocks provide dedicated simple dual-port or single-port memory up to 18-bits wide at up to 318 MHz. M512 blocks are grouped into columns across the device in between certain LABs.

M4K RAM blocks are true dual-port memory blocks with 4K bits plus parity (4,608 bits). These blocks provide dedicated true dual-port, simple dual-port, or single-port memory up to 36-bits wide at up to 291 MHz. These blocks are grouped into columns across the device in between certain LABs.

M-RAM blocks are true dual-port memory blocks with 512K bits plus parity (589,824 bits). These blocks provide dedicated true dual-port, simple dual-port, or single-port memory up to 144-bits wide at up to 269 MHz. Several M-RAM blocks are located individually or in pairs within the device's logic array.

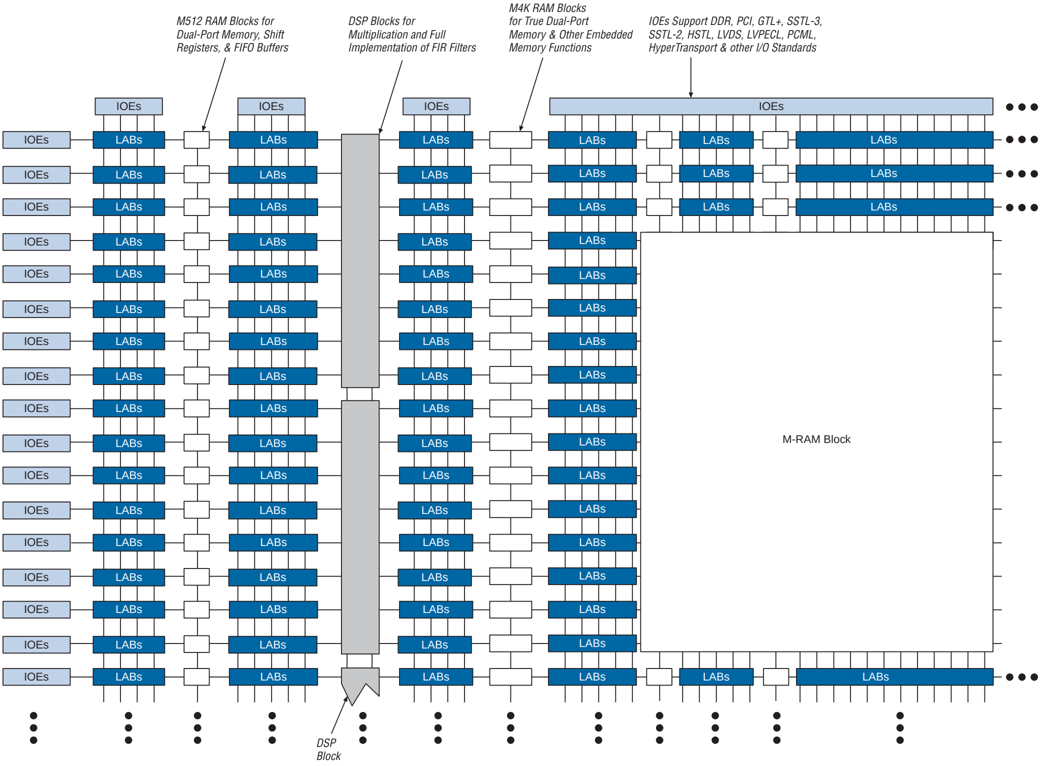
Digital signal processing (DSP) blocks can implement up to either eight full-precision 9 × 9-bit multipliers, four full-precision 18 × 18-bit multipliers, or one full-precision 36 × 36-bit multiplier with add or subtract features. These blocks also contain 18-bit input shift registers for digital signal processing applications, including FIR and infinite impulse response (IIR) filters. DSP blocks are grouped into two columns in each device.

Each Stratix GX device I/O pin is fed by an I/O element (IOE) located at the end of LAB rows and columns around the periphery of the device. I/O pins support numerous single-ended and differential I/O standards. Each IOE contains a bidirectional I/O buffer and six registers for registering input, output, and output-enable signals. When used with dedicated clocks, these registers provide exceptional performance and interface support with external memory devices such as DDR SDRAM, FCRAM, ZBT, and QDR SRAM devices.

High-speed serial interface channels support transfers at up to 840 Mbps using LVDS, LVPECL, 3.3-V PCML, or HyperTransport technology I/O standards.

Figure 1–2 shows an overview of the Stratix GX device.

Figure 1–2. Stratix GX Block Diagram

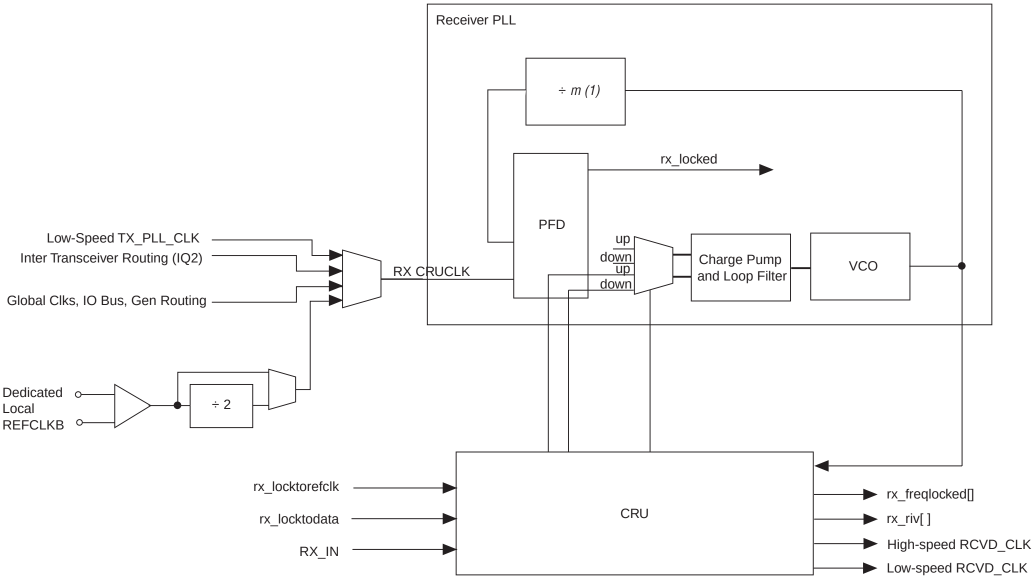


The number of M512 RAM, M4K RAM, and DSP blocks varies by device along with row and column numbers and M-RAM blocks. Table 1–5 lists the resources available in Stratix GX devices.

Table 1–5. Stratix GX Device Resources

Device	M512 RAM Columns/Blocks	M4K RAM Columns/Blocks	M-RAM Blocks	DSP Block Columns/Blocks	LAB Columns	LAB Rows
EP1SGX10	4 / 94	2 / 60	1	2 / 6	40	30
EP1SGX25	6 / 224	3 / 138	2	2 / 10	62	46
EP1SGX40	8 / 384	3 / 183	4	2 / 14	77	61

Figure 2–13. Receiver PLL & CRU Circuit



Note to Figure 2–13:

(1) *m* = 8, 10 16, or 20.

The receiver PLLs and CRUs are capable of supporting up to 3.1875 Gbps. The input clock frequency for –5 and –6 speed grade devices is limited to 650 MHz if you use the `REFCLKB` pin or 325 MHz if you use the other clock routing resources. The maximum input clock frequency for –7 speed grade devices is 312.5 MHz if you use the `REFCLKB` pin or 156.25 MHz with the other clock routing resources. An optional `RX_LOCKED` port (active low signal) is available to indicate whether the PLL is locked to the reference clock. The receiver PLL has a programmable loop bandwidth, which can be set to low, medium, or high. The loop bandwidth parameter can be statically set by the Quartus II software.

Table 2–5 lists the adjustable parameters of the receiver PLL and CRU. All the parameters listed are statically programmable in the Quartus II software.

Table 2–5. Receiver PLL & CRU Adjustable Parameters (Part 1 of 2)

Parameter	Specifications
Input reference frequency range	25 MHz to 650 MHz
Data rate support	500 Mbps to 3.1875 Gbps

3. Source-Synchronous Signaling With DPA

SGX51003-1.1

Introduction

Expansion in the telecommunications market and growth in Internet use requires systems to move more data faster than ever. To meet this demand, rely on solutions such as differential signaling and emerging high-speed interface standards including RapidIO, POS-PHY 4, SFI-4, or XSBI.

These new protocols support differential data rates up to 1 Gbps and higher. At these high data rates, it becomes more challenging to manage the skew between the clock and data signals. One solution to this challenge is to use CDR to eliminate skew between data channels and clock signals. Another potential solution, DPA, is beginning to be incorporated into some of these protocols.

The source-synchronous high-speed interface in Stratix GX devices is a dedicated circuit embedded into the PLD allowing for high-speed communications. The *High-Speed Source-Synchronous Differential I/O Interfaces in Stratix GX Devices* chapter of the *Stratix GX Device Handbook, Volume 2* provides information on the high-speed I/O standard features and functions of the Stratix GX device.

Stratix GX I/O Banks

Stratix GX devices contain 17 I/O banks. I/O banks one and two support high-speed LVDS, LVPECL, and 3.3-V PCML inputs and outputs. These two banks also incorporate an embedded dynamic phase aligner within the source-synchronous interface (see Figure 3–8 on page 3–10). The dynamic phase aligner corrects for the phase difference between the clock and data lines caused by skew. The dynamic phase aligner operates automatically and continuously without requiring a fixed training pattern, and allows the source-synchronous circuitry to capture data correctly regardless of the channel-to-clock skew.

Principles of SERDES Operation

Stratix GX devices support source-synchronous differential signaling up to 1 Gbps in DPA mode, and up to 840 Mbps in non-DPA mode. Serial data is transmitted and received along with a low-frequency clock. The PLL can multiply the incoming low-frequency clock by a factor of 1 to 10. The SERDES factor *J* can be 8 or 10 for the DPA mode, or 4, 7, 8, or 10 for all other modes. The SERDES factor does not have to equal the clock

Table 4–10. M-RAM Combined Byte Selection for ×144 Mode Notes (1), (2)

byteena[15..0]	datain ×144
[0] = 1	[8..0]
[1] = 1	[17..9]
[2] = 1	[26..18]
[3] = 1	[35..27]
[4] = 1	[44..36]
[5] = 1	[53..45]
[6] = 1	[62..54]
[7] = 1	[71..63]
[8] = 1	[80..72]
[9] = 1	[89..81]
[10] = 1	[98..90]
[11] = 1	[107..99]
[12] = 1	[116..108]
[13] = 1	[125..117]
[14] = 1	[134..126]
[15] = 1	[143..135]

Notes to Tables 4–9 and 4–10:

(1) Any combination of byte enables is possible.

(2) Byte enables can be used in the same manner with 8-bit words, that is, in ×16, ×32, ×64, and ×128 modes.

Similar to all RAM blocks, M-RAM blocks can have different clocks on their inputs and outputs. All input registers—`renwe`, `datain`, address, and byte enable registers—are clocked together from either of the two clocks feeding the block. The output register can be bypassed. The eight `labclk` signals or local interconnect can drive the control signals for the A and B ports of the M-RAM block. LEs can also control the `clock_a`, `clock_b`, `renwe_a`, `renwe_b`, `clr_a`, `clr_b`, `clocken_a`, and `clocken_b` signals as shown in Figure 4–18.

Figure 4–21. M-RAM Row Unit Interface to Interconnect

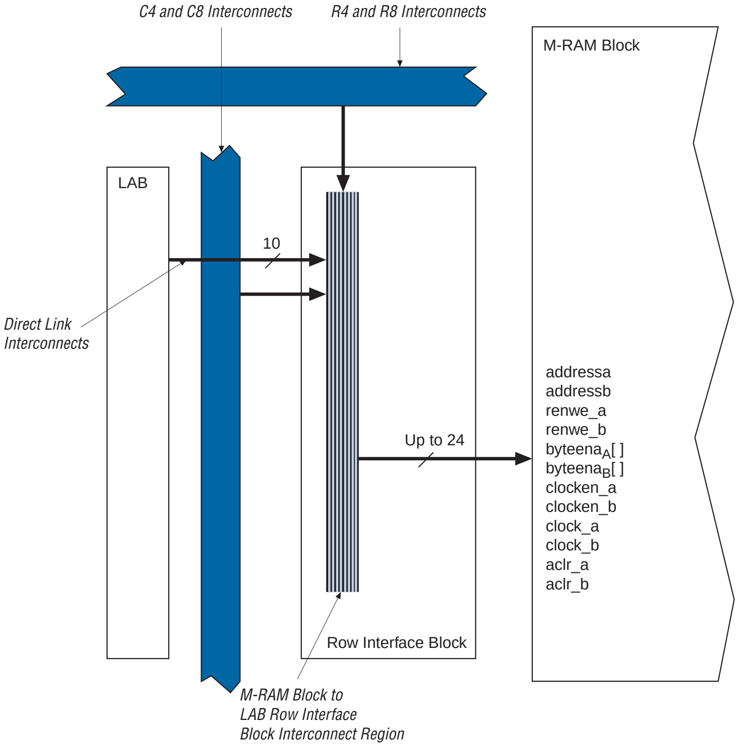
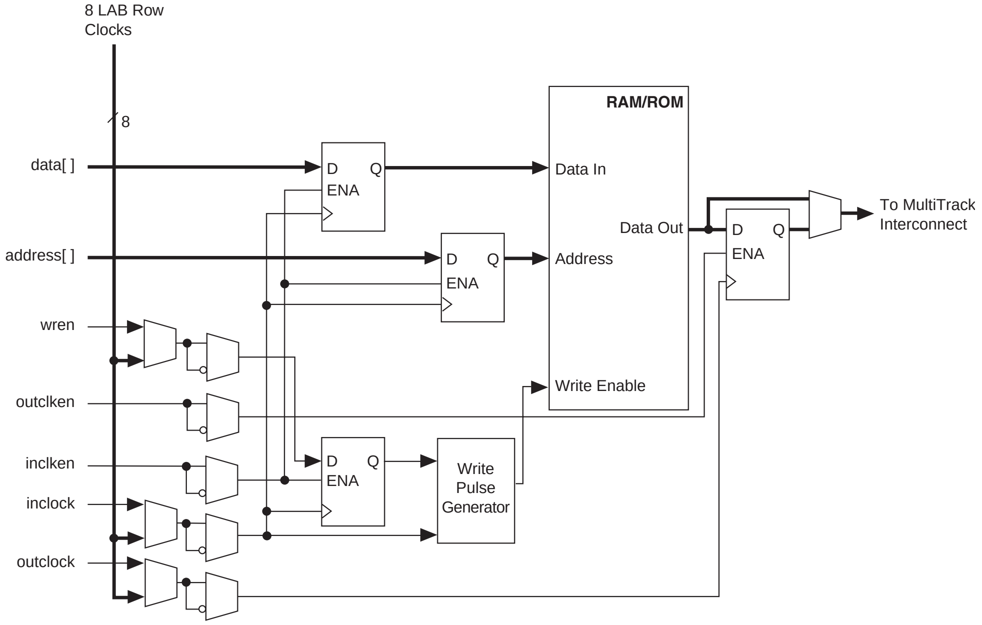


Figure 4–27. Single-Port Mode



Digital Signal Processing Block

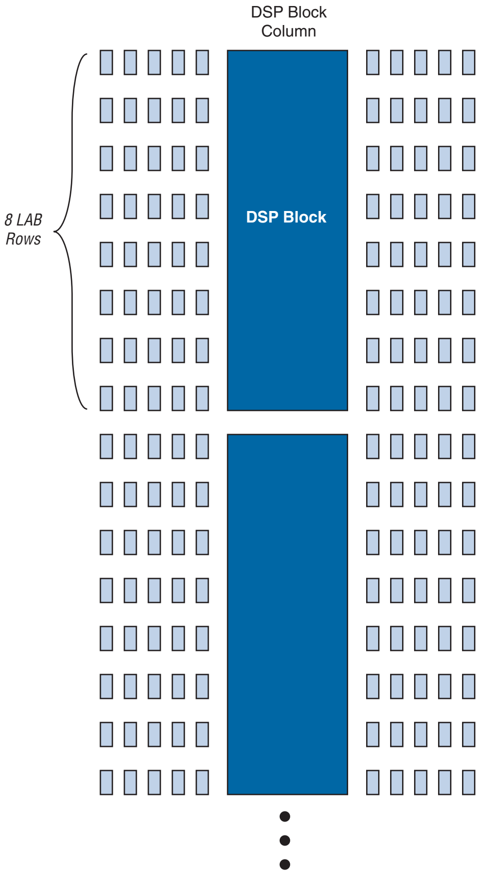
The most commonly used DSP functions are finite impulse response (FIR) filters, complex FIR filters, infinite impulse response (IIR) filters, fast Fourier transform (FFT) functions, direct cosine transform (DCT) functions, and correlators. All of these blocks have the same fundamental building block: the multiplier. Additionally, some applications need specialized operations such as multiply-add and multiply-accumulate operations. Stratix GX devices provide DSP blocks to meet the arithmetic requirements of these functions.

Each Stratix GX device has two columns of DSP blocks to efficiently implement DSP functions faster than LE-based implementations. Larger Stratix GX devices have more DSP blocks per column (see Table 4–12). Each DSP block can be configured to support up to:

- Eight 9 × 9-bit multipliers
- Four 18 × 18-bit multipliers
- One 36 × 36-bit multiplier

As indicated, the Stratix GX DSP block can support one 36 × 36-bit multiplier in a single DSP block. This is true for any matched sign multiplications (either unsigned by unsigned or signed by signed), but

Figure 4–28. DSP Blocks Arranged in Columns



Input Registers

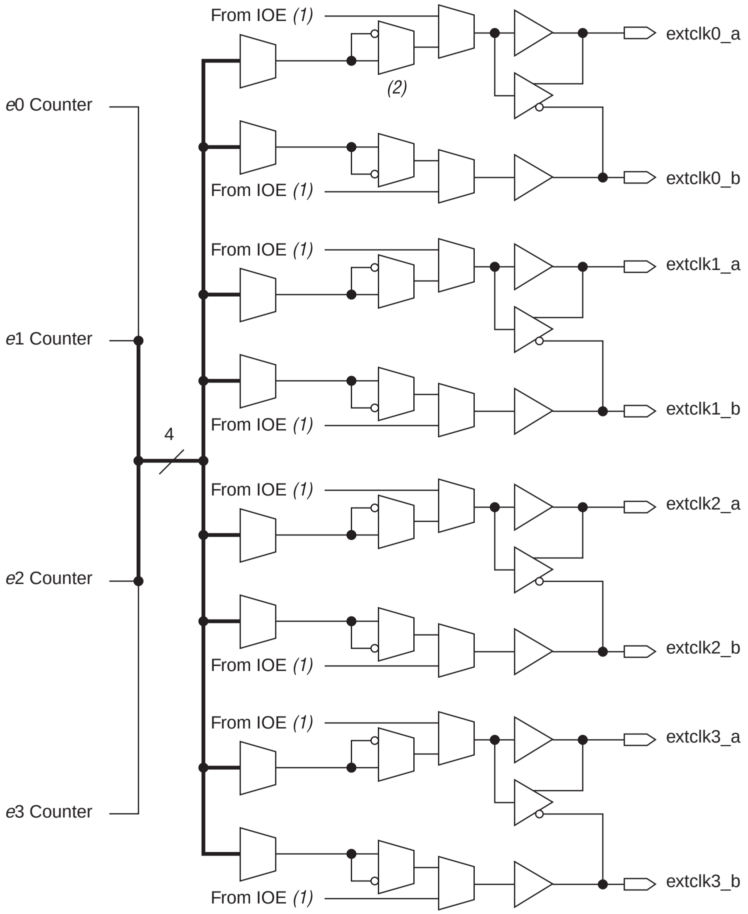
A bank of optional input registers is located at the input of each multiplier and multiplicand inputs to the multiplier. When these registers are configured for parallel data inputs, they are driven by regular routing resources. You can use a clock signal, asynchronous clear signal, and a clock enable signal to independently control each set of A and B inputs for each multiplier in the DSP block. You select these control signals from a set of four different `clock[3..0]`, `aclr[3..0]`, and `ena[3..0]` signals that drive the entire DSP block.

You can also configure the input registers for a shift register application. In this case, the input registers feed the multiplier and drive two dedicated shift output lines: `shiftoutA` and `shiftoutB`. The shift outputs of one multiplier block directly feed the adjacent multiplier block in the same DSP block (or the next DSP block) as shown in Figure 4–32, to form a shift register chain. This chain can terminate in any block, that is, you can create any length of shift register chain up to 224 registers. You can use the input shift registers for FIR filter applications. One set of shift inputs can provide data for a filter, and the other are coefficients that are optionally loaded in serial or parallel. When implementing 9 × 9- and 18 × 18-bit multipliers, you do not need to implement external shift registers in LAB LEs. You implement all the filter circuitry within the DSP block and its routing resources, saving LE and general routing resources for general logic. External registers are needed for shift register inputs when using 36 × 36-bit multipliers.

External Clock Outputs

Enhanced PLLs 5 and 6 each support up to eight single-ended clock outputs (or four differential pairs). See Figure 4–54.

Figure 4–54. External Clock Outputs for PLLs 5 & 6



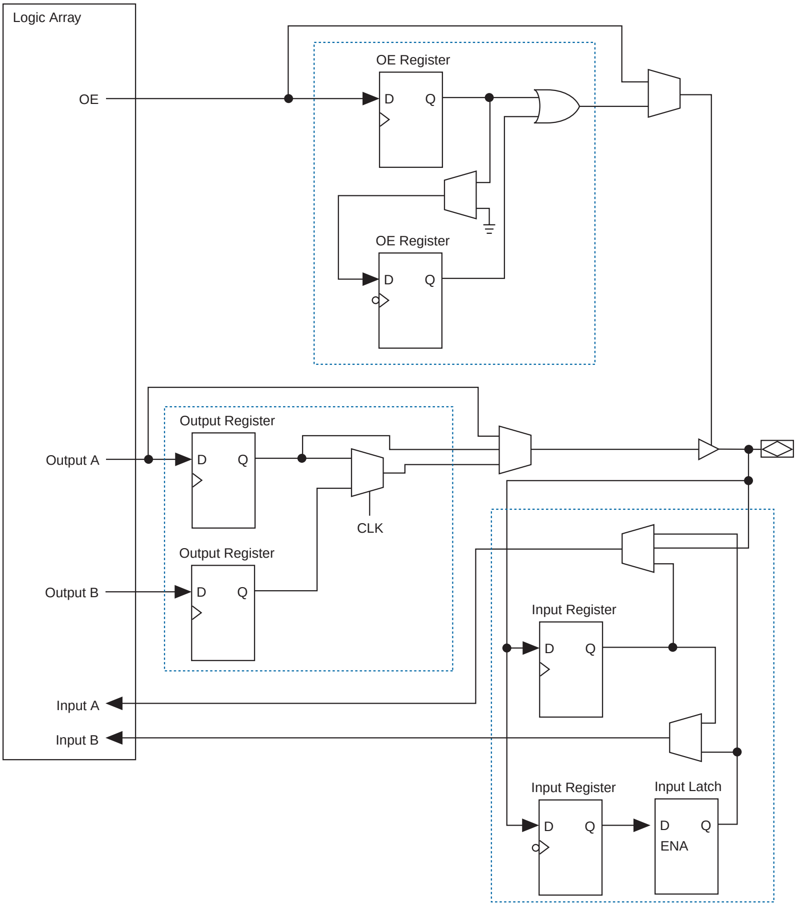
Notes to Figure 4–54:

(1) Each external clock output pin can be used as a general purpose output pin from the logic array. These pins are multiplexed with IOE outputs.

(2) Two single-ended outputs are possible per output counter—either two outputs of the same frequency and phase or one shifted 180°.

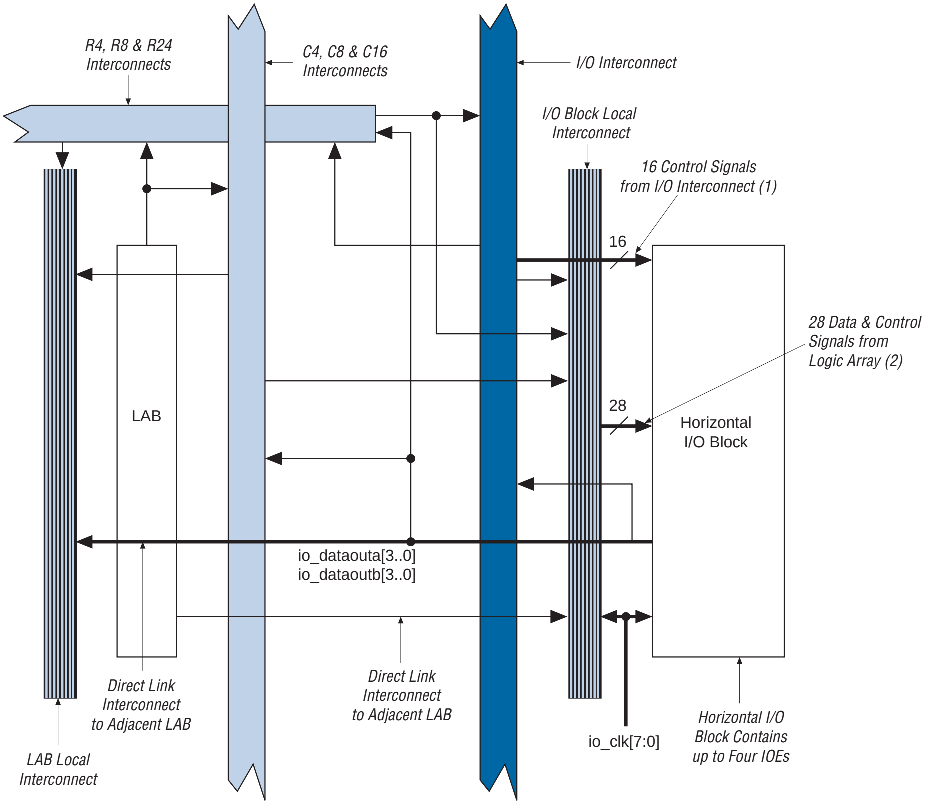
Any of the four external output counters can drive the single-ended or differential clock outputs for PLLs 5 and 6. This means one counter or frequency can drive all output pins available from PLL 5 or PLL 6. Each

Figure 4–58. Stratix GX IOE Structure



The IOEs are located in I/O blocks around the periphery of the Stratix GX device. There are up to four IOEs per row I/O block and six IOEs per column I/O block. The row I/O blocks drive row, column, or direct link interconnects. The column I/O blocks drive column interconnects. Figure 4–59 shows how a row I/O block connects to the logic array. Figure 4–60 shows how a column I/O block connects to the logic array.

Figure 4–59. Row I/O Block Connection to the Interconnect



Notes to Figure 4–59:

(1) The 16 control signals are composed of four output enables `io_boe[3..0]`, four clock enables `io_bce[3..0]`, four clocks `io_clk[3..0]`, and four clear signals `io_bclr[3..0]`.

(2) The 28 data and control signals consist of eight data out lines: four lines each for DDR applications `io_dataouta[3..0]` and `io_dataoutb[3..0]`, four output enables `io_coe[3..0]`, four input clock enables `io_cce_in[3..0]`, four output clock enables `io_cce_out[3..0]`, four clocks `io_cclk[3..0]`, and four clear signals `io_cclr[3..0]`.

Programmable delays can increase the register-to-pin delays for output and/or output enable registers. A programmable delay exists to increase the t_{ZX} delay to the output pin, which is required for ZBT interfaces. Table 4–21 shows the programmable delays for Stratix GX devices.

Table 4–21. Stratix GX Programmable Delay Chain

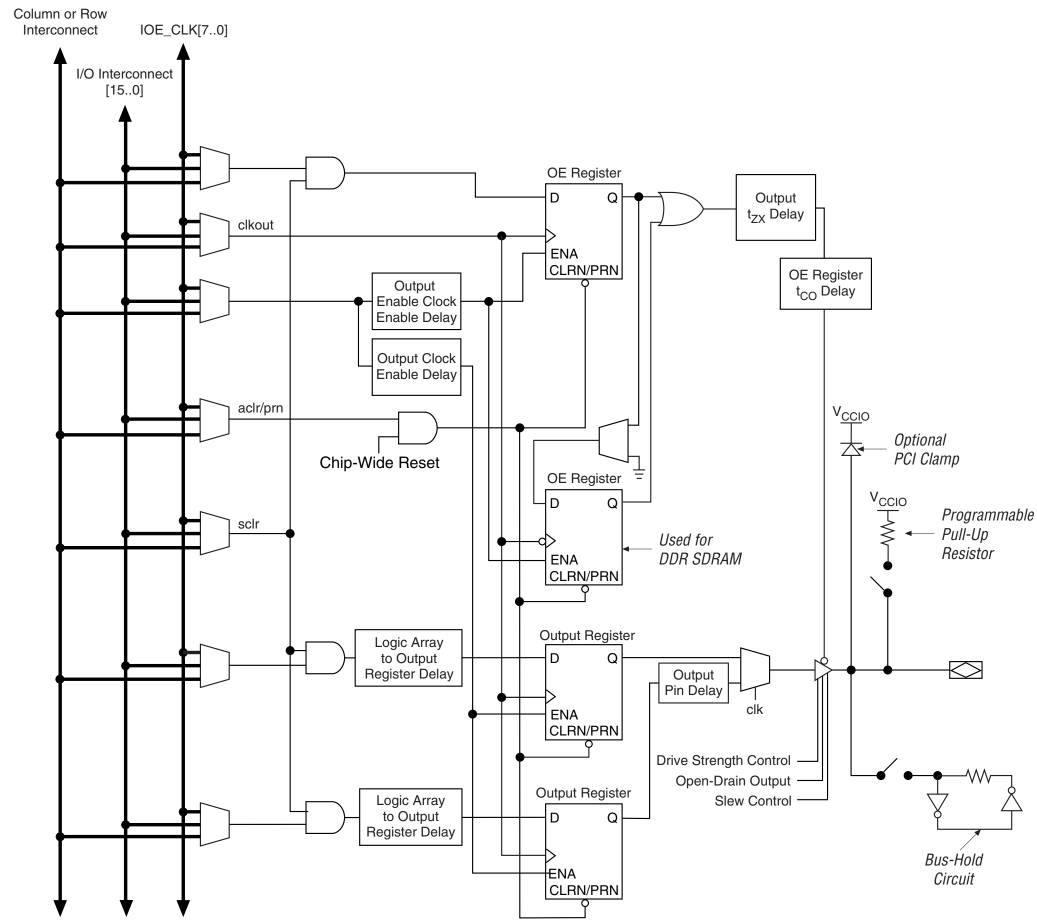
Programmable Delays	Quartus II Logic Option
Input pin to logic array delay	Decrease input delay to internal cells
Input pin to input register delay	Decrease input delay to input register
Output pin delay	Increase delay to output pin
Output enable register t_{CO} delay	Increase delay to output enable pin
Output t_{ZX} delay	Increase t_{ZX} delay to output pin
Output clock enable delay	Increase output clock enable delay
Input clock enable delay	Increase input clock enable delay
Logic array to output register delay	Decrease input delay to output register
Output enable clock enable delay	Increase output enable clock enable delay

The IOE registers in Stratix GX devices share the same source for clear or preset. You can program preset or clear for each individual IOE. You can also program the registers to power up high or low after configuration is complete. If programmed to power up low, an asynchronous clear can control the registers. If programmed to power up high, an asynchronous preset can control the registers. This feature prevents the inadvertent activation of another device's active-low input upon power-up. If one register in an IOE uses a preset or clear signal then all registers in the IOE must use that same signal if they require preset or clear. Additionally, a synchronous reset signal is available for the IOE registers.

Double-Data Rate I/O Pins

Stratix GX devices have six registers in the IOE, which support DDR interfacing by clocking data on both positive and negative clock edges. The IOEs in Stratix GX devices support DDR inputs, DDR outputs, and bidirectional DDR modes.

Figure 4–66. Stratix GX IOE in DDR Output I/O Configuration *Notes (1), (2)*



Notes to Figure 4–66:

(1) All input signals to the IOE can be inverted at the IOE.

(2) The tristate is by default active high. It can, however, be designed to be active low.

Table 4–28. I/O Support by Bank (Part 2 of 2)

I/O Standard	Top & Bottom Banks (3, 4, 7 & 8)	Left Banks (1 & 2)	Enhanced PLL External Clock Output Banks (9, 10, 11 & 12)
SSTL-3 class II	✓	✓	✓
AGP (1× and 2×)	✓		✓
CTT	✓	✓	✓

Each I/O bank has its own `VCCIO` pins. A single device can support 1.5-, 1.8-, 2.5-, and 3.3-V interfaces; each bank can support a different standard independently. Each bank also has dedicated `VREF` pins to support any one of the voltage-referenced standards (such as SSTL-3) independently.

Each I/O bank can support multiple standards with the same V_{CCIO} for input and output pins. Each bank can support one voltage-referenced I/O standard. For example, when V_{CCIO} is 3.3 V, a bank can support LVTTL, LVCMOS, 3.3-V PCI, and SSTL-3 for inputs and outputs.

Differential On-Chip Termination

Stratix GX devices provide differential on-chip termination (LVDS I/O standard) to reduce reflections and maintain signal integrity. Differential on-chip termination simplifies board design by minimizing the number of external termination resistors required. Termination can be placed inside the package, eliminating small stubs that can still lead to reflections. The internal termination is designed using transistors in the linear region of operation.

Stratix GX devices support internal differential termination with a nominal resistance value of 137.5 Ω for LVDS input receiver buffers. LVPECL signals require an external termination resistor. Figure 4–70 shows the device with differential termination.

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

All Stratix GX devices provide JTAG BST circuitry that complies with the IEEE Std. 1149.1a-1990 specification. JTAG boundary-scan testing can be performed either before or after, but not during configuration. Stratix GX devices can also use the JTAG port for configuration together with either the Quartus II software or hardware using either Jam Files (**.jam**) or Jam Byte-Code Files (**.jbc**).

Stratix GX devices support IOE I/O standard setting reconfiguration through the JTAG BST chain. The JTAG chain can update the I/O standard for all input and output pins any time before or during user mode. You can use this ability for JTAG testing before configuration when some of the Stratix GX pins drive or receive from other devices on the board using voltage-referenced standards. Because the Stratix GX device may not be configured before JTAG testing, the I/O pins may not be configured for appropriate electrical standards for chip-to-chip communication. Programming those I/O standards via JTAG allows you to fully test I/O connection to other devices.

The enhanced PLL reconfiguration bits are part of the JTAG chain before configuration and after power-up. After device configuration, the PLL reconfiguration bits are not part of the JTAG chain.

Stratix GX devices also use the JTAG port to monitor the logic operation of the device with the SignalTap® embedded logic analyzer. Stratix GX devices support the JTAG instructions shown in Table 4–33.

Table 4–33. Stratix GX JTAG Instructions (Part 1 of 2)

JTAG Instruction	Description
`SAMPLE/PRELOAD`	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern to be output at the device pins. Also used by the SignalTap® embedded logic analyzer.
`EXTEST` *(1)*	Allows the external circuitry and board-level interconnects to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
`BYPASS`	Places the 1-bit bypass register between the `TDI` and `TDO` pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation.
`USERCODE`	Selects the 32-bit `USERCODE` register and places it between the `TDI` and `TDO` pins, allowing the `USERCODE` to be serially shifted out of `TDO`.
`IDCODE`	Selects the IDCODE register and places it between `TDI` and `TDO`, allowing the IDCODE to be serially shifted out of `TDO`.
`HIGHZ` *(1)*	Places the 1-bit bypass register between the `TDI` and `TDO` pins, which allows the BST data to pass synchronously through selected devices to adjacent devices during normal device operation, while tri-stating all of the I/O pins.

Table 6–45. IOE Internal Timing Microparameters

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{SU}	64		68		68		ps
t_{H}	76		80		80		ps
t_{CO}		162		171		171	ps
$t_{PIN2COMBOUT\_R}$		1,038		1,093		1,256	ps
$t_{PIN2COMBOUT\_C}$		927		976		1,122	ps
$t_{COMBIN2PIN\_R}$		2,944		3,099		3,563	ps
$t_{COMBIN2PIN\_C}$		3,189		3,357		3,860	ps
t_{CLR}	262		276		317		ps
t_{PRE}	262		276		317		ps
t_{CLKHL}	90		95		109		ps

Table 6–46. DSP Block Internal Timing Microparameters

Symbol	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	
t_{SU}	0		0		0		ps
t_{H}	67		75		86		ps
t_{CO}		142		158		181	ps
$t_{INREG2PIPE18}$		2,613		2,982		3,429	ps
$t_{INREG2PIPE9}$		3,390		3,993		4,591	ps
$t_{PIPE2OUTREG2ADD}$		2,002		2,203		2,533	ps
$t_{PIPE2OUTREG4ADD}$		2,899		3,189		3,667	ps
t_{PD9}		3,709		4,081		4,692	ps
t_{PD18}		4,795		5,275		6,065	ps
t_{PD36}		7,495		8,245		9,481	ps
t_{CLR}	450		500		575		ps
t_{CLKHL}	1,350		1,500		1,724		ps

Table 6–50. Stratix GX Transceiver Reset & PLL Lock Time Parameters

Symbol	Min	Typ	Max	Units
$t_{ANALOGRESETPW}$ *(5)*	1			mS
$t_{DIGITALRESETPW}$ *(5)*	4			Parallel clock cycle
$t_{TX\_PLL\_LOCK}$ *(3)*			10	µS
$t_{RX\_FREQLOCK}$ *(4)*			5	mS
$t_{RX\_FREQLOCK2PHASELOCK}$ *(2)*			5	µS

Notes to Table 6–50:

(1) The minimum pulse width specified is associated with the power-down of circuits.

(2) The clock recovery unit (CRU) phase locked-to-data time is based on a data rate of 500 Mbps and 8B/10B encoded data.

(3) After `#pll_areset`, `pll_enable`, or PLL power-up, the time required for the transceiver PLL to lock to the reference clock.

(4) After `#rx_analogreset`, the time for the CRU to switch to lock-to-data mode.

(5) There is no maximum pulse width specification. The GXB can be held in reset indefinitely.

Routing delays vary depending on the load on a specific routing line. The Quartus II software reports the routing delay information when running the timing analysis for a design. Contact Altera Applications Engineering for more details.

External Timing Parameters

External timing parameters are specified by device density and speed grade. Figure 6–6 shows the timing model for bidirectional IOE pin timing. All registers are within the IOE.

Table 6–86. High-Speed Timing Specifications & Definitions (Part 2 of 2)

High-Speed Timing Specification	Definitions
t_{FALL}	High-to-low transmission time.
Timing unit interval (TUI)	The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency × Multiplication Factor) = t_C/w).
f_{HSDR}	Maximum/minimum LVDS data transfer rate (f_{HSDR} = 1/TUI), non-DPA.
$f_{HSDRDPA}$	Maximum/minimum LVDS data transfer rate ($f_{HSDRDPA}$ = 1/TUI), DPA.
Channel-to-channel skew (TCCS)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew. The clock is included in the TCCS measurement.
Sampling window (SW)	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window. SW = t_{SW} (max) – t_{SW} (min).
Input jitter (peak-to-peak)	Peak-to-peak input jitter on high-speed PLLs.
Output jitter (peak-to-peak)	Peak-to-peak output jitter on high-speed PLLs.
t_{DUTY}	Duty cycle on high-speed transmitter output clock.
t_{LOCK}	Lock time for high-speed transmitter and receiver PLLs.

Table 6–87 shows the high-speed I/O timing specifications for Stratix GX devices.

Table 6–87. High-Speed I/O Specifications (Part 1 of 4) Notes (1), (2)

Symbol	Conditions	-5 Speed Grade			-6 Speed Grade			-7 Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HSCLK} (Clock frequency) (LVDS, LVPECL, HyperTransport technology) f_{HSCLK} = f_{HSDR} / W	W = 1 to 30 for $\leq$717 Mbps W = 2 to 30 for > 717 Mbps	10		717	10		717	10		624	MHz
f_{HSCLK_DPA}		74		717	74		717	74		717	MHz

Table 6–92. Fast PLL Specifications for -7 & -8 Speed Grades (Part 2 of 2)

Symbol	Parameter	Min	Max	Unit
t_{DUTY}	Duty cycle for `DFFIO` 1× `CLKOUT` pin *(3)*	45	55	%
t_{JITTER}	Period jitter for DIFFIO clock out *(3)*		±80	ps
	Period jitter for internal global or regional clock		±100 ps for >200 MHz `outclk` ±20 mUI for <200 MHz `outclk`	ps or mUI
t_{LOCK}	Time required for PLL to acquire lock	10	100	µs
m	Multiplication factors for *m* counter *(4)*	1	32	Integer
*l*0, *l*1, *g*0	Multiplication factors for *l*0, *l*1, and *g*0 counter *(4)*, *(5)*	1	32	Integer
t_{ARESET}	Minimum pulse width on `areset` signal	10		ns

Notes to Tables 6–91 & 6–92:

(1) See "Maximum Input & Output Clock Rates" on page 6–54.

(2) When using the SERDES, high-speed differential I/O mode supports a maximum output frequency of 210 MHz to the global or regional clocks (that is, the maximum data rate 840 Mbps divided by the smallest SERDES J factor of 4).

(3) This parameter is for high-speed differential I/O mode only.

(4) These counters have a maximum of 32 if programmed for 50/50 duty cycle. Otherwise, they have a maximum of 16.

(5) High-speed differential I/O mode supports *W* = 1 to 16 and *J* = 4, 7, 8, or 10.

DLL Jitter

Table 6–93 reports the jitter for the DLL in the DQS phase-shift reference circuit.

Table 6–93. DLL Jitter for DQS Phase Shift Reference Circuit

Frequency (MHz)	DLL Jitter (ps)
197 to 200	± 100
160 to 196	± 300
100 to 159	± 500